

## MOS FIELD EFFECT TRANSISTOR 2SK3574

### SWITCHING N-CHANNEL POWER MOS FET

#### **DESCRIPTION**

The 2SK3574 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

#### **FEATURES**

- •4.5V drive available
- •Low on-state resistance

RDS(on)1 = 13.5 m $\Omega$  MAX. (VGS = 10 V, ID = 24 A)

Low gate charge

 $Q_G = 22 \text{ nC TYP}$ .  $(V_{DD} = 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 48 \text{ A})$ 

- •Built-in gate protection diode
- Avalanche capability ratings
- •Surface mount device available

#### **★ ORDERING INFORMATION**

PART NUMBER	PACKAGE		
2SK3574	TO-220AB		
2SK3574-S	TO-262		
2SK3574-ZK	TO-263		
2SK3574-Z	TO-220SMD <sup>Note</sup>		

Note TO-220SMD package is produced only in Japan.

#### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vss = 0 V)	Voss	30	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	ID(DC)	±48	Α
Drain Current (pulse) Note1	ID(pulse)	±140	Α
Total Power Dissipation (T <sub>A</sub> = 25°C)	P <sub>T1</sub>	1.5	W
Total Power Dissipation (Tc = 25°C)	P <sub>T2</sub>	29	W
Channel Temperature	Tch	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C
Single Avalanche Current Note2	las	19	Α
Single Avalanche Energy Note2	Eas	36	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1%

2. Starting Tch = 25°C, VDD = 15 V, Rg = 25  $\Omega$ , Vgs = 20  $\rightarrow$  0 V

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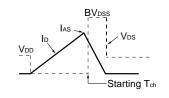


**ELECTRICAL CHARACTERISTICS (TA = 25°C)** 

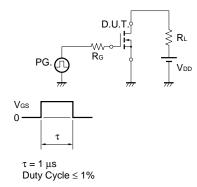
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			10	μΑ
Gate Leakage Current	Igss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5		2.5	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 24 A	7.0			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 24 A		10.1	13.5	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 15 A		15	24	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V		940		pF
Output Capacitance	Coss	Vgs = 0 V		245		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		170		pF
Turn-on Delay Time	td(on)	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 24 A		12		ns
Rise Time	<b>t</b> r	Vgs = 10 V		18		ns
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 10 \Omega$		39		ns
Fall Time	<b>t</b> f			12		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 24 V		22		nC
Gate to Source Charge	Qgs	Vgs = 10 V		3.8		nC
Gate to Drain Charge	Q <sub>GD</sub>	ID = 48 A		7		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 48 A, VGS = 0 V		1.1		V
Reverse Recovery Time	trr	IF = 48 A, VGS = 0 V		29		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		24.8		nC

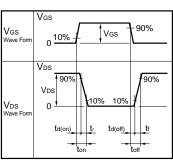
#### **★** TEST CIRCUIT 1 AVALANCHE CAPABILITY

# $\begin{array}{c} \text{D.U.T.} \\ \text{RG} = 25 \ \Omega \\ \text{VGS} = 20 \rightarrow 0 \ \text{V} \end{array} \begin{array}{c} \text{PG.} \\ \text{PG.} \\ \text{PG.} \\ \text{PG.} \\ \text{PG.} \end{array} \begin{array}{c} \text{D.U.T.} \\ \text{PG.} \\ \text$



#### **TEST CIRCUIT 2 SWITCHING TIME**

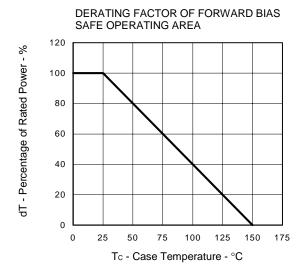


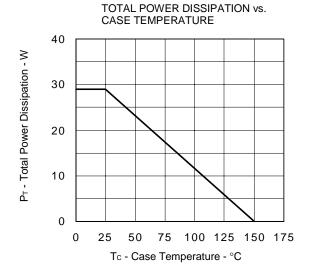


#### **TEST CIRCUIT 3 GATE CHARGE**

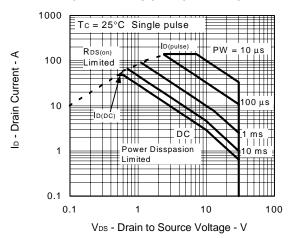


#### TYPICAL CHARACTERISTICS (TA = 25°C)

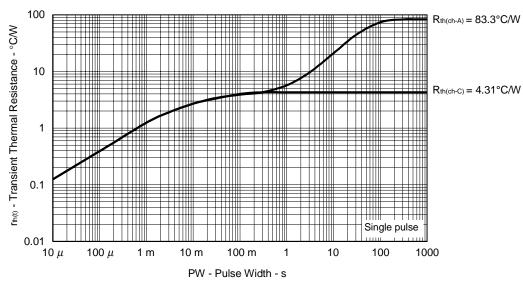




#### FORWARD BIAS SAFE OPERATING AREA

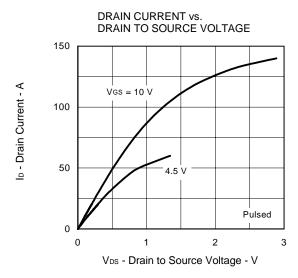


#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

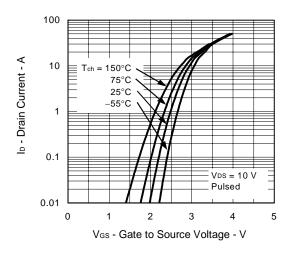


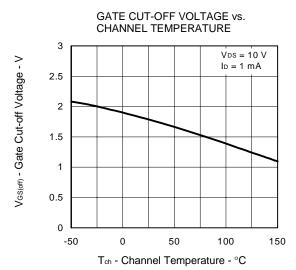
3



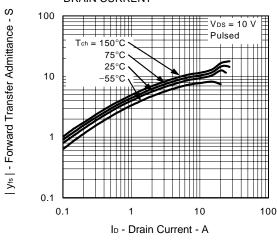


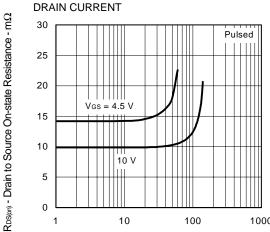
#### FORWARD TRANSFER CHARACTERISTICS



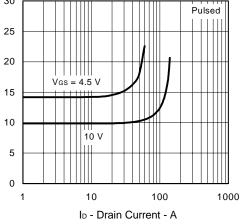


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

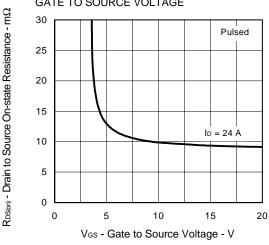




DRAIN TO SOURCE ON-STATE RESISTANCE vs.

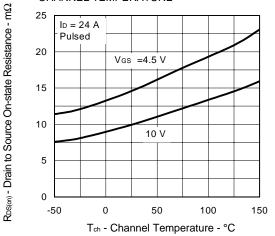


DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

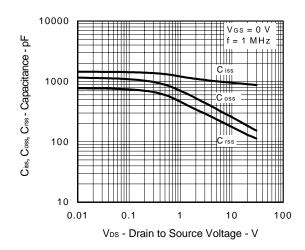




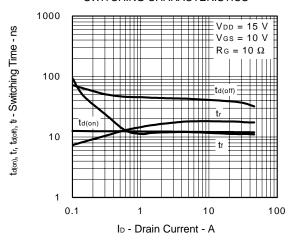
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



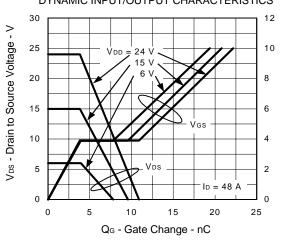
#### CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



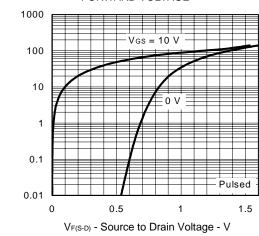
SWITCHING CHARACTERISTICS



DYNAMIC INPUT/OUTPUT CHARACTERISTICS

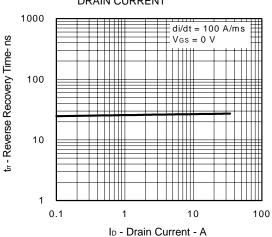


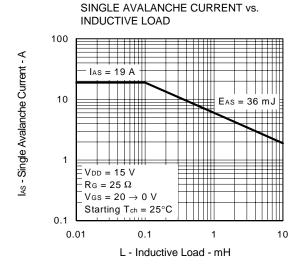
SOURCE TO DRAIN DIODE FORWARD VOLTAGE

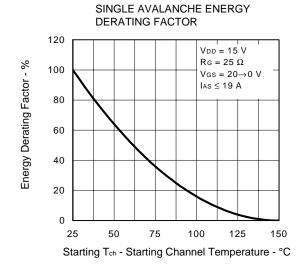


IF - Diode Forward Current - A

REVERSE RECOVERY TIME vs. DRAIN CURRENT



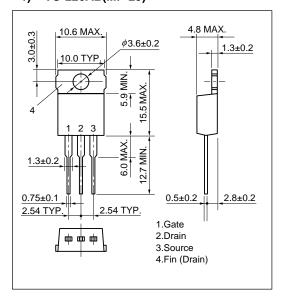




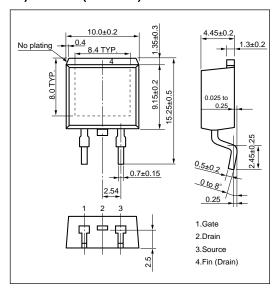


#### **★ PACKAGE DRAWINGS (Unit: mm)**

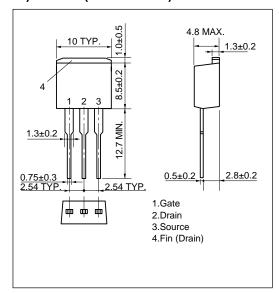
#### 1) TO-220AB(MP-25)



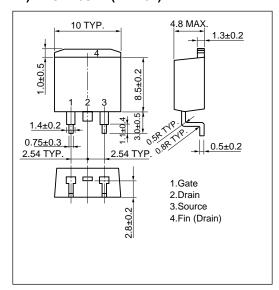
#### 3) TO-263(MP-25ZK)



#### 2) TO-262(MP-25 Fin Cut)

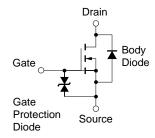


#### 4) TO-220SMD(MP-25Z)<sup>Note</sup>



**Note** This package is produced only in Japan.

#### **EQUIVALENT CIRCUIT**



#### Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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